

(19)

Europäisches Patentamt

European Patent Office

Office européen des brevets



(11)

EP 1 024 547 A2

(12)

EUROPEAN PATENT APPLICATION

(43) Date of publication:
02.08.2000 Bulletin 2000/31

(51) Int. Cl.⁷: H01P 1/205, H01P 1/213

(21) Application number: 00100433.2

(22) Date of filing: 10.01.2000

(84) Designated Contracting States:
AT BE CH CY DE DK ES FI FR GB GR IE IT LI LU
MC NL PT SE
Designated Extension States:
AL LT LV MK RO SI

• Kato, Hideyuki,
Murata Manufacturing Co., Ltd.
Nagaokakyo-shi, Kyoto-fu 617-8555 (JP)
• Hiroshima, Motoharu,
Murata Manufact. Co., Ltd.
Nagaokakyo-shi, Kyoto-fu 617-8555 (JP)

(30) Priority: 28.01.1999 JP 1976799

(71) Applicant:
Murata Manufacturing Co., Ltd.
Nagaokakyo-shi Kyoto-fu 617-8555 (JP)

(74) Representative:
Schoppe, Fritz, Dipl.-Ing. et al
Schoppe, Zimmermann & Stöckeler,
Patentanwälte,
Postfach 71 08 67
81458 München (DE)

(72) Inventors:
• Tada, Hitoshi,
Murata Manufacturing Co., Ltd.
Nagaokakyo-shi, Kyoto-fu 617-8555 (JP)

(54) Dielectric filter, dielectric duplexer, and communication apparatus

(57) There is disclosed a dielectric filter comprising: an attenuation band in proximity to a pass band; a threshold-frequency position (B) of a determined maximum insertion loss being arranged close to a shoulder portion of a waveform exhibiting pass characteristics in which insertion losses increase in a region from the pass band to the attenuation band; temperature characteristics of a dielectric material being determined in such a manner that the shoulder portion moves toward the attenuation-band direction according to an increase and decrease in temperature. In the above dielectric filter, the deterioration of insertion-loss characteristics with respect to temperature changes is improved so that good characteristics are exhibited over a wide range of temperatures.

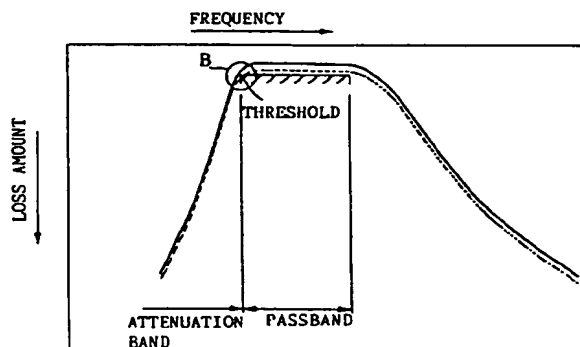


FIG. 3B

EP 1 024 547 A2

Description

BACKGROUND OF THE INVENTION

1. Field of the Invention

[0001] The present invention relates to a dielectric filter, a dielectric duplexer, and a communication apparatus incorporating the same, in which a dielectric material is used in a resonator part.

2. Description of the Related Art

[0002] Generally, for example, when a dielectric duplexer is formed by disposing a plurality of dielectric resonators in a dielectric block, a plurality of resonant-line holes are arranged in the dielectric block to form resonant lines on the inner surfaces of the holes, by which there are provided a transmitting filter section, in which signals of a transmitting band are allowed to pass through and signals of a receiving band are attenuated, and a receiving filter section, in which signals of the receiving band are allowed to pass through and signals of the transmitting band are attenuated.

[0003] When the transmitting filter and the receiving filter are band-pass type filters, pass characteristics of the filters are as shown in Figs. 14A and 14B. In this case, the symbol Tx denotes the pass characteristics of the transmitting filter, and the symbol Rx denotes the pass characteristics of the receiving filter. As indicated by hatching F1, F2, F3 and F4 in the figures, a maximum insertion loss in a transmitting band (F1) and a minimum insertion loss in a receiving band (F2) are determined as the characteristics of the transmitting filter, whereas a maximum insertion loss in the receiving band (F3) and a minimum insertion loss in the transmitting band (F4) are determined as the characteristics of the receiving filter. The transmitting filter and the receiving filter are designed so that they can satisfy these conditions.

[0004] However, the pass characteristics shown in Figs. 14A and 14B are the characteristics at a specified temperature. In general, in dielectric filters and dielectric duplexers, the higher the temperature, the more the unloaded Q factor (Q_0) of a resonator is deteriorated. This is due to the temperature characteristics of electrode materials. For example, in the case of silver or copper, conductivity decreases by approximately 2% with an increase of every 10°C. The conductivity decrease of the electrode directly leads to the deterioration of Q_0 . As a result, the higher the temperature, the more the insertion loss of the filter is deteriorated.

[0005] In general, since the characteristics of a pass band are determined by a maximum insertion loss and a region specifying a frequency range (from one threshold frequency to the other threshold frequency) thereof, both shoulder portions of the pass band characteristics (the portions A and B shown in Figs. 14A and

14B) are in proximity to the ends of the region. In addition, in the case of a duplexer, since a transmitting band and a receiving band are conventionally in proximity to each other, the shoulder portion in a range from the pass band to the attenuation band thereof is the closest to the end of a side close to the attenuation band in a region specifying the maximum insertion loss and the frequency range thereof (the position indicating the maximum insertion loss and the frequency range is hereinafter referred to as a "threshold").

[0006] For example, the filter (the transmitting filter) on the lower-frequency side of the pass band has a threshold on the higher-frequency side of the pass band, as shown at a portion A Fig. 14A. The filter (the receiving filter) on the higher-frequency side of the pass band has a threshold on the lower-frequency side of the pass band, as shown at a portion B.

[0007] In this case, when the temperature of the dielectric duplexer is increased, Q_0 of a resonator is deteriorated due to the above-described reason, by which insertion losses are increased as indicated by dotted lines in Fig. 14A. Furthermore, when the temperature is over a certain degree, both the high-frequency side shoulder portion of the pass characteristics of the transmitting filter and the low-frequency side shoulder portion of the pass characteristics of the receiving filter go beyond the maximum insertion loss at each of the thresholds.

[0008] Although the example shown in Fig. 14A illustrates a case where the permittivity-temperature characteristics of the dielectric material are fixed (in which permittivity does not change regardless of temperature changes), when the dielectric material has permittivity-temperature characteristics, as shown in Fig. 14B, according to the inclination of the characteristics, the pass characteristics move toward either the high-frequency side or the low-frequency side. For example, when the higher the temperature is the lower the permittivity so that the resonant frequency is increased, pass characteristics as indicated by dotted lines in Fig. 14B are exhibited. In this case, the shoulder portion of the pass characteristics of the receiving filter having an attenuation band on the lower-frequency side goes beyond the maximum insertion loss of the threshold, as shown at the portion B. Furthermore, as shown in Fig. 14A, the waveform of the pass characteristics does not only move toward the lower direction, but it moves toward the right-lower slanting direction in the figure. Therefore, the problems described above occur even at relatively low temperatures.

[0009] The above-described problems occur not only in the case of a dielectric duplexer, but the problems also occur in the case of a single dielectric filter in which a threshold is in proximity to the shoulder portion where insertion losses increase in a region from the pass band to the attenuation band.

SUMMARY OF THE INVENTION

[0010] To overcome the above described problems, preferred embodiments of the present invention provide a dielectric filter, a dielectric duplexer, and a communication apparatus incorporating the same, in which deterioration of insertion-loss characteristics with respect to temperature changes is improved so that good characteristics are exhibited over a wide range of temperatures. In this invention, even if temperature changes occur in a dielectric filter or a dielectric duplexer, a waveform exhibiting the pass characteristics of the device is moved in such a manner that the waveform does not go beyond a threshold determined by a maximum insertion loss and a threshold frequency thereof.

[0011] One preferred embodiment of the present invention provides a dielectric filter having an attenuation band in proximity to a pass band, a threshold-frequency position of a determined maximum insertion loss being arranged close to a shoulder portion of a waveform exhibiting pass characteristics in which insertion losses increase in a region from the pass band to the attenuation band. In this dielectric filter, temperature characteristics of a dielectric material are determined in such a manner that the shoulder portion moves toward the attenuation-band direction according to an increase and decrease in temperature. With this arrangement, even if the pass characteristics of the filter change according to an increase and decrease in temperature, since the shoulder portion in the region from the pass band to the attenuation band moves in such a manner that they avoid a threshold, by which specified characteristics can be maintained.

[0012] The above described dielectric filter may be formed by a plurality of dielectric resonators, at least one of the dielectric resonators being a trap resonator forming an attenuation pole in a region from the shoulder portion to the attenuation band. In addition, the temperature characteristics of the dielectric material are determined in such a manner that resonant-frequency changes with respect to temperature changes in the trap resonator are smaller than those with respect to temperature changes in the other dielectric resonator. With this arrangement, attenuation characteristics near the attenuation pole are fixed regardless of temperature changes, so that specified attenuation characteristics can be maintained.

[0013] Furthermore, the plurality of the dielectric resonators may be integrally molded or integrally fired as a single dielectric block. Although there is a problem in that, if a dielectric filter is formed by combining discrete dielectric resonators, an error in the arrangement occurs, since the difference in the temperature characteristics of a dielectric material cannot be judged from the appearance, the present invention can solve the problem.

[0014] The above described dielectric filter may be a band pass filter formed by a plurality of dielectric res-

onators in which the pass band is used as the range of a resonant frequency. With this arrangement, the insertion loss of the pass band is smaller and the insertion loss at the shoulder portion of the pass band adjacent to the attenuation band can be maintained at a low level over a wide range of temperatures.

[0015] The dielectric filter may be a band block filter formed by a plurality of dielectric resonators in which the attenuation band is used as the range of a resonant frequency. With this arrangement, a large amount of attenuation in the attenuation band can be obtained, and at the same time, the insertion loss at the shoulder portion of the pass band adjacent to the attenuation band can be maintained at a low level over a wide range of temperatures.

[0016] Another preferred embodiment of the present invention provides a dielectric duplexer including the above-described two dielectric filters, one of the two filters being a dielectric filter in which the low-frequency band of the filter is an attenuation band and the high-frequency band thereof is a pass band, and the other filter being a dielectric filter in which the low-frequency band of the filter is a pass band and the high-frequency band thereof is an attenuation band. With this arrangement, in both filters, the shoulder portion of the pass characteristics in the region from the pass band to the attenuation band does not go beyond a maximum insertion loss over a wide range of temperatures, by which the functions of the duplexer can be maintained. In addition, in this dielectric duplexer, when the two dielectric filters are integrally molded or integrally fired by a single dielectric block, the above-described error in the arrangement does not occur.

[0017] Yet another preferred embodiment of the present invention provides a communication apparatus including one of the dielectric filter and the dielectric duplexer described above, which is disposed in a high-frequency circuit section. With this arrangement, a communication apparatus in which a specified signal-processing function of the high-frequency circuit section can be maintained over a wider range of temperatures.

[0018] Other features and advantages of the present invention will become apparent from the following description of the invention which refers to the accompanying drawings.

BRIEF DESCRIPTION OF DRAWINGS

[0019]

Figs. 1A, 1b, 1C and 1D are projection views of a dielectric filter according to a first embodiment of the present invention.

Fig. 2 is an equivalent circuit diagram of the dielectric filter.

Figs. 3A and 3B are pass characteristic graphs of the dielectric filter.

Fig. 4 is a graph showing an example of frequency-

temperature changes according to the difference in dielectric materials.

Figs. 5A, 5B, 5C and 5D are projection views of a dielectric filter according to a second embodiment of the present invention.

Fig. 6 is an equivalent circuit diagram of the dielectric filter.

Fig. 7 is a pass characteristic graph of the dielectric filter.

Fig. 8 is an equivalent circuit diagram of a dielectric filter according to a third embodiment of the present invention.

Fig. 9 is a pass characteristic graph of the dielectric filter.

Figs. 10A, 10B, 10C and 10D are projection views of a dielectric duplexer according to a fourth embodiment of the present invention.

Fig. 11 is an equivalent circuit diagram of the dielectric duplexer.

Figs. 12A and 12B are pass characteristic graphs of the dielectric duplexer.

Fig. 13 is a block diagram showing the structure of a communication apparatus according to a fifth embodiment of the present invention.

Figs. 14A and 14B are pass characteristic graphs of a conventional dielectric duplexer.

DESCRIPTION OF THE PREFERRED EMBODIMENTS

[0020] The structure of a dielectric filter according to a first embodiment of the present invention will be illustrated by referring to Figs. 1 to 4.

[0021] Figs. 1A to 1D are projection views of the dielectric filter, in which Fig. 1A is a plan view, Fig. 1B is a front view, Fig. 1C is a bottom view, and Fig. 1D is a right side view. When the dielectric filter is mounted on a printed circuit board as a component, the front view shown in Fig. 1B is a surface mounted, with respect to the printed circuit board.

[0022] This dielectric filter is formed by disposing various holes and electrodes with respect to a rectangular parallelepiped dielectric block 1. More particularly, reference numerals 2a, 2b, and 2c denote resonant-line holes, on the inner surfaces of which resonant lines 12a, 12b, and 12c are formed. In addition, reference numerals 3a and 3b denote input/output coupling line holes, on the inner surfaces of which input/output coupling lines 13a and 13b are formed. These holes are stepped holes where the inner diameters of the through-holes are changed at certain points thereof. On the outer surfaces of a dielectric block 1, input/output terminals 7 and 8 continuing from the input/output coupling lines 13a and 13b are formed, and on substantially the entire surfaces (six faces) except these input/output terminals, ground electrodes 10 are formed. In addition, on the resonant lines 12a, 12b, and 12c, electrodeless portions (non-conductive portions) indicated by "g" are dis-

posed near the ends of the large inner-diameter sides of the stepped holes to generate stray capacitances (Cs) at these parts.

[0023] The operations of the dielectric filter having the above structure will be described. First, the resonant lines 12a, 12b, and 12c formed in the resonant-line holes 2a, 2b, and 2c are capacitively coupled. In other words, the resonant lines 12a, 12b, and 12c are coupled by a combination of the comb-line coupling (inductive coupling) formed by the above Cs and the capacitive coupling formed by the stepped holes. In this case, since a relationship of the inductive coupling < the capacitive coupling is provided, the resonant lines 12a, 12b, and 12c are capacitively coupled overall. Interdigital coupling is each formed between the resonant line 12a and the input/output coupling line 13a and between the resonant line 12c and the input/output coupling line 13b. With this arrangement, the part between the input terminals 7 and 8 serves as a band pass filter.

[0024] Fig. 2 is an equivalent circuit diagram of the dielectric filter. In this figure, the symbols Za, Zb, and Zc denote impedances generated by the resonant lines 12a, 12b, and 12c shown in Fig. 1, and the symbols Zi and Zo denote impedances generated by the input/output coupling lines 13a and 13b shown in Fig. 1. In addition, the symbol Zia denotes an impedance generated by a mutual capacitance generated between the resonant line 12a and the input/output coupling line 13a, the symbol Zco denotes an impedance generated by a mutual capacitance generated between the resonant line 12c and the input/output coupling line 13b. Furthermore, the symbol Zab denotes an impedance generated by a mutual capacitance generated between the resonant lines 12a and 12b, and the symbol Zbc denotes an impedance generated by a mutual capacitance between the resonant lines 12b and 12c.

[0025] Figs. 3A and 3B show graphs illustrating the pass characteristics of the dielectric filter. In this example, an attenuation pole is formed on the lower-frequency side of the pass band by the capacitive coupling, in which a steep attenuation characteristic is obtained in a region from the pass band to the attenuation band on the lower-frequency side. The hatched parts in the figure show maximum insertion losses and the frequency ranges thereof. At normal temperatures, the shoulder portions of the waveforms indicating the pass characteristics in the regions from the pass bands to the lower-frequency sides of the attenuation bands are in proximity to thresholds. However, the insertion losses in the pass bands, as indicated by solid lines in the graphs, are smaller than the maximum insertion losses. Although another threshold exists at the end of higher-frequency side of the hatched part, the higher-frequency side region of the pass band is not considered here.

[0026] The dielectric block has a positive permittivity-temperature coefficient. As a result, the pass characteristics of the dielectric filter at high temperatures move

toward a low-frequency band direction, as indicated by a dotted line in each graph. In addition, according to the conductivity-temperature coefficient of an electrode, Q_0 is deteriorated and an insertion loss thereby increases. As a result, with temperature rise, the entire waveform of the pass characteristics moves toward a left-lower slanting direction in each graph. As shown in the Fig. 3A, even at high temperatures, the shoulder portion of the waveform exhibiting the pass characteristics does not go beyond the threshold.

[0027] If the dielectric filter is formed by using a dielectric material whose permittivity-temperature coefficient is approximately zero, since the pass characteristics move toward the lower direction in the graph, as shown in Fig. 3B, the shoulder portion indicated by the symbol B goes beyond the threshold at a certain temperature.

[0028] Fig. 4 shows the temperature characteristics of two dielectric materials. Regarding the resonant frequency of a dielectric resonator using the dielectric material exhibiting the characteristics indicated by a solid line, when 25°C is a reference temperature, as the temperature becomes higher than that, the resonant frequency is reduced, in which when the temperature is +85°C, the resonant frequency changes by -5 ppm. Even when the temperature is lower than 25°C, the resonant frequency is reduced, in which when the temperature is -35°C, the resonant frequency changes by -5 ppm. In addition, regarding the resonant frequency of a dielectric resonator using the dielectric material exhibiting the characteristics indicated by a dotted line in the graph, when 25°C is a reference temperature, as the temperature becomes higher than that, the resonant frequency is increased, in which when the temperature is +85°C, the resonant frequency changes by +5 ppm. Even when the temperature is lower than 25°C, the resonant frequency is increased, in which when the temperature is -35°C the resonant frequency changes by +5 ppm. Furthermore, when the dielectric resonator is formed by using a dielectric material exhibiting the characteristics indicated by a dash-single-dot line in the graph, the resonant frequency of the resonator does not almost change over the range of -35°C and +85°C.

[0029] In Fig. 4, as a dielectric material exhibiting the upwardly-protruded type characteristics, BaO-PbO-Nd₂O₃-TiO₂ can be used.

[0030] As a dielectric material exhibiting the downwardly-protruded type characteristics,

BaO-Bi₂O₃-Nd₂O₃-Sm₂O₃-TiO₂ can be used.

[0031] As a dielectric material exhibiting the flat characteristic,

BaO-PbO-Bi₂O₃-Nd₂O₃-TiO₂

can be used. In addition, a permittivity-temperature coefficient (a frequency-temperature coefficient in the case of a dielectric filter) can be arbitrarily determined by changing the compositional ratios of these materials. Such a resonant frequency/temperature change is determined by the permittivity-temperature coefficient

of the dielectric block. However, in general, since the temperature characteristics of a dielectric material is obtained by measuring a resonant frequency obtained when a dielectric resonator is formed, the temperature characteristics of a dielectric material are indicated by a frequency/temperature coefficient (hereinafter referred to as TC).

[0032] In the dielectric filter having the characteristics shown in Fig. 3A, the frequency is lowered as the temperature increases up to 25°C or higher, as indicated by the symbol A shown in Fig. 4. In other words, a dielectric material in which TC is less than 0 is used.

[0033] Next, the structure of a dielectric filter according to a second embodiment will be illustrated by referring to Figs. 5A to 7.

[0034] Figs. 5A to 5D are projection views of the dielectric filter, in which Fig. 5A is a plan view, Fig. 5B is a front view, Fig. 5C is a bottom view, and Fig. 5D is a right side view. When the dielectric filter is mounted on a printed circuit board as a component, the front view shown in Fig. 5B is a surface mounted with respect to the printed circuit board.

[0035] The dielectric filter is formed by disposing various holes and electrodes with respect to a rectangular parallelepiped dielectric block 1. Unlike the structure shown in Fig. 1, in this embodiment, a resonant-line hole 2d is additionally disposed in the dielectric block 1, and a resonant line 12d is formed on the inner surface of the resonant-line hole 2d. Furthermore, at substantially the center of the input/output coupling line hole 3b, there is given a boundary position, by which the dielectric block in the direction of the resonant-line hole 2d has a material in which TC is 0, and the dielectric block in the other region has a material in which TC is smaller than 0. The other structural parts are the same those shown in Fig. 1. When the dielectric block is formed, the dielectric material in which TC is smaller than 0 and the dielectric material in which TC is 0 are integrally molded and fired. In this case, since the dielectric materials, whose basic compositions are the same, are molded and fired, the performances are substantially the same. As a result, molding and firing can be simultaneously conducted.

[0036] The operation of the dielectric filter shown in Figs. 5A to 5D will be illustrated as follows. First, resonant lines 12a, 12b, and 12c formed in resonant-line holes 2a, 2b, and 2c are capacitively coupled. As in the case of the first embodiment, the resonant lines 12a, 12b, and 12c are coupled by a combination of the comb-line coupling (inductive coupling) formed by the stray capacitances C_s of electrodeless portions g and the capacitive coupling formed by stepped holes. In this case, since a relationship of inductive coupling < capacitive coupling is provided, the resonant lines 12a, 12b, and 12c are capacitively coupled overall. Interdigital coupling is each formed between the resonant line 12a and an input/output coupling line 13a and between the resonant line 12c and an input/output coupling line 13b.

With this arrangement, the part between input/output terminals 7 and 8 serves as a band pass filter. A resonant line 12d is interdigitally coupled to the input/output coupling line 13b to serve as a trap resonator.

[0037] Fig. 6 is an equivalent circuit diagram of the dielectric filter, in which the symbol Z_d denotes an impedance generated by the resonant line 12d, and the symbol Z_{do} denotes an impedance generated by the mutual capacitance generated between an impedance Z_o generated by the input/output coupling line 13b and the resonant line 12d. The other parts are the same as those in the equivalent circuit shown in Fig. 2.

[0038] Fig. 7 is a graph illustrating the pass characteristics of the dielectric filter. In this embodiment, an attenuation pole is generated by the resonant line 12d serving as the trap resonator. With this arrangement, a steep attenuation characteristic is exhibited in a range from the pass band to the attenuation band of the lower-frequency side. The hatched part in the pass band shown in the figure indicates a maximum insertion loss and the frequency range thereof, and the hatched part in the attenuation band indicates a minimum attenuation and the frequency range thereof. At normal temperatures, although the shoulder portion in a region from the pass band of a waveform exhibiting the pass characteristics to the attenuation band of the lower-frequency side thereof is in proximity to a threshold, an insertion loss in the pass band is smaller than the maximum insertion loss, as indicated by a solid line in the figure. As shown in Fig. 5, since the TC of the dielectric material of the band pass filter section is smaller than zero, the waveform exhibiting the pass characteristics of the dielectric filter at high temperatures moves toward a left-lower slanting direction overall, as indicated by a dotted line in the figure. In this situation, the shoulder portion of the waveform exhibiting the pass characteristics does not go beyond the threshold. In addition, since the TC of the dielectric material of the resonant-line hole 2d is equal to 0, the frequency of an attenuation pole is fixed regardless of temperature changes. With this arrangement, the attenuation in the attenuation band can be constantly provided, and the determined minimum attenuation in the attenuation band can thereby be constantly provided.

[0039] Next, the structure of a dielectric filter according to a third embodiment will be illustrated by referring to Figs. 8 and 9.

[0040] Although the above embodiments use dielectric filters having pass-band characteristics, similarly, band-block type dielectric filters can also be applied. Fig. 8 shows an equivalent circuit of a band-block type dielectric filter. In the figure, the symbols Z_b , Z_d , and Z_f denote each impedance of resonant lines, and the symbols Z_{bd} and Z_{df} denote each impedance generated by the mutual capacitance obtained when these lines are interdigitally coupled. In addition, the symbols Z_a , Z_c , and Z_e denote each impedance of the resonant lines as trap resonators, and the symbol Z_{ab} denotes an imped-

ance generated by the mutual capacitance between resonators Z_a and Z_b to operate as a $\pi/2$ phase circuit, by which (Z_a and Z_{ab}) operate as a trap resonator. Similarly, the symbol Z_{cd} denotes an impedance generated by the mutual capacitance between resonators Z_d and Z_c , by which (Z_c and Z_{cd}) operate as a trap resonator; and the symbol Z_{ef} denotes an impedance generated by the mutual capacitance between resonators Z_f and Z_e , in which (Z_f and Z_{ef}) operate as a trap resonator. Thus, this is a structure in which the trap resonators of three stages are coupled.

[0041] Fig. 9 is a graph illustrating the pass characteristics of the dielectric filter. In this figure, the shoulder portion of the pass characteristics in a region from the pass band to the attenuation band is in proximity to a threshold. The TC of the dielectric material of a dielectric block is larger than 0. As a result, at high temperatures, the waveform of the pass characteristics moves toward a right-lower slanting direction, as indicated by a dotted line. With this arrangement, even at high temperatures, the shoulder of the waveform does not go beyond the maximum value of pass losses.

[0042] Next, the structure of a dielectric duplexer according to a fourth embodiment of the present invention will be illustrated by referring to Figs. 10A to 12.

[0043] Figs. 10A to 10D are projection views of the dielectric duplexer, in which Fig. 10A is a plan view, Fig. 10B is a front view, Fig. 10C is a bottom view, and Fig. 10D is a right side view. When this dielectric duplexer is mounted on a printed circuit board as a component, the front surface shown in Fig. 10B is a surface to be mounted with respect to the printed circuit board.

[0044] The above dielectric duplexer is formed by disposing various holes and electrodes with respect to a rectangular parallelepiped dielectric block 1. To put it concretely, reference numerals 2a, 2b, and 2c denote resonant-line holes, on the inner surfaces of which resonant lines 12a, 12b, and 12c are formed. Similarly, reference numerals 5a, 5b, and 5c denote resonant-line holes, on the inner surfaces of which resonant lines 15a, 15b, and 15c are formed. In addition, reference numerals 3a, 3b, and 3c denote input/output coupling line holes, on the inner surfaces of which input/output coupling lines 13a, 13b, and 13c are formed. These holes are stepped holes in which the inner diameters of the holes are changed at a certain point thereof. On an outer surface of the dielectric block 1, input/output terminals 7, 8, and 9 continuing from the input/output coupling line holes 13a, 13b, and 13c are formed, and on substantially the entire surfaces (six surfaces) except the parts of these input/output terminals, ground electrodes 10 are formed. Furthermore, near the ends of the large-diameter side of the stepped holes having the resonant lines 12a, 12b, 12c, 15a, 15b, and 15c, electrodeless portions (nonconductive portions) indicated by the symbol "g" are disposed, at each of which a stray capacitance (C_s) is generated.

[0045] The above-described dielectric block 1 has

four dielectric-material regions including $TC = 0$, $TC > 0$, $TC < 0$, and $TC = 0$, as shown in Fig. 10B.

[0046] Next, the operation of the dielectric duplexer will be illustrated as follows. First, the resonant lines 12a, 12b, and 12c formed in the resonant-line holes 2a, 2b, and 2c are inductively coupled. The resonant lines 12a, 12b, and 12c are coupled by a combination of the comb-line coupling (inductive coupling) formed by the stray capacitance C_s of the electrodeless portions g and the capacitive coupling formed by the stepped holes. However, in this case, a relationship of the inductive coupling $>$ the capacitive coupling is provided, the resonant lines 12a, 12b, and 12c are inductively coupled overall. Interdigital coupling is each formed between the resonant line 12a and the input/output coupling line 13a and between the resonant line 12c and the input/output coupling line 13b. In addition, interdigital coupling is formed between a resonant line 12d and an input/output coupling line 13b.

[0047] Meanwhile, the resonant lines 15a, 15b, and 15c are capacitively coupled. The resonant lines 15a, 15b, and 15c are coupled by a combination of the comb-line coupling (inductive coupling) formed by the stray capacitance C_s of electrodeless portions g and the capacitive coupling formed by the stepped holes. In this case, since there is provided a relationship of inductive coupling $<$ capacitive coupling, the resonant lines 15a, 15b, and 15c are capacitively coupled overall. Interdigital coupling is each formed between the resonant line 15a and the input/output coupling line 13c and between the resonant line 15c and the input/output coupling line 13a, and interdigital coupling is formed between a resonant line 15d and the input/output coupling line 13c.

[0048] Fig. 11 is an equivalent circuit diagram of the dielectric filter described above. The symbols Z_{1a} , Z_{1b} , and Z_{1c} denote each impedance generated by the resonant lines 15a, 15b, and 15c shown in Fig. 10, the symbol Z_{1d} denotes an impedance generated by the resonant line 15d, the symbol Z_{2d} denotes an impedance generated by the resonant line 12d. The symbols Z_{2a} , Z_{2b} , and Z_{2c} denote each impedance generated by the resonant lines 12a, 12b, and 12c shown in Fig. 10, and the symbols Z_{1i} , Z_{1o} , Z_{2o} denote each impedance generated by the input/output coupling lines 13c, 13a, and 13b shown in Fig. 1. The symbol Z_{1id} denotes an impedance generated by the mutual capacitance generated between the resonant line 15d and the input/output coupling line 13c, and the symbol Z_{2od} denotes an impedance generated by the mutual capacitance generated between the resonant line 12d and the input/output coupling line 13b. The symbol Z_{1ab} denotes an impedance generated by the mutual capacitance generated between the resonant lines 15a and 15b, the symbol Z_{1bc} denotes an impedance generated by the mutual capacitance generated between the resonant lines 15b and 15c, the symbol Z_{2ab} denotes an impedance generated by the mutual capacitance generated between the resonant lines 12a and 12b, and the

symbol Z_{2bc} denotes an impedance generated by the mutual capacitance generated between the resonant lines 12b and 12c. Furthermore, the symbol Z_{1co} denotes an impedance generated by the mutual capacitance generated between the resonant line 15c and the input/output coupling line 13a, and the symbol Z_{2ai} denotes an impedance generated by the mutual capacitance generated between the resonant line 12a and the input/output coupling line 13a.

[0049] In this way, each of a transmitting filter and a receiving filter is formed by the resonators of three stages and the trap resonator of one stage.

[0050] Figs. 12A and 12B are graphs illustrating the pass characteristics of the dielectric duplexer. In this example, a transmitting filter allows signals of a transmitting band to pass through, and allows signals of a receiving band on the high-frequency side to be attenuated. The receiving filter allows signals of the receiving band to pass through and allows signals of the transmitting band on the low-frequency side to be attenuated. In the transmitting filter, an attenuation band made by the above-described trap resonator is formed on the high-frequency side of the pass band, and in the receiving filter, an attenuation band made by the above-described trap resonator is formed on the low-frequency side of the pass band.

[0051] The hatched parts in each graph indicate maximum insertion losses and minimum attenuations, and the frequency ranges thereof. At normal temperatures, the shoulder portions in regions from the pass bands to the attenuation bands of waveforms exhibiting pass characteristics are in proximity to thresholds. However, the insertion losses in the pass bands are smaller than the maximum insertion losses, as indicated by solid lines in the figure.

[0052] The TC is larger than 0 in the dielectric material of the resonator part producing the band pass characteristics of the transmitting filter. Therefore, the waveform exhibiting the pass characteristics of the transmitting filter at high temperatures moves toward a right-lower slanting direction, as indicated by a dotted line. As a result, as shown in Fig. 12A, even at high temperatures, in the transmitting filter, the shoulder portion of the waveform exhibiting the pass characteristics does not go beyond the threshold. In addition, the TC is smaller than 0 in the dielectric material of the resonator part producing the band pass characteristics of the receiving filter. Therefore, the waveform exhibiting the pass characteristics of the receiving filter at high temperatures moves toward a left-lower slanting direction. As a result, as shown in Fig. 12A, even at high temperatures, in the receiving filter, the shoulder portion of the waveform exhibiting the pass characteristics does not go beyond the threshold. Furthermore, since the TC is equal to 0 in the dielectric material of the resonator parts producing the band pass characteristics of each of the transmitting filter and the receiving filter, even at high temperatures, it is possible to constantly provide an

attenuation in the receiving band of the transmitting filter and an attenuation in the transmitting band of the receiving filter.

[0053] A material indicated by the symbol B in Fig. 4 is used as the dielectric material of the resonator part 5 producing the band pass characteristics of the above transmitting filter, and a material indicated by the symbol A in Fig. 4 is used as the dielectric material of the resonator part producing the band pass characteristics of the above receiving filter. As a result, at temperatures 10 lower than 25°C, as shown in Fig. 12B, the pass band characteristics of the transmitting filter move toward a right-upper slanting direction in the figure, and the pass band characteristics of the receiving filter move toward a left-upper slanting direction in the figure. Accordingly, 15 at lower temperatures, insertion losses in both the transmitting filter and the receiving filter are more satisfactory.

[0054] Fig. 13 is a block diagram illustrating the structure of a communication apparatus according to a 20 fifth embodiment. In this figure, the symbol ANT denotes a transmitting/receiving antenna, the symbol DPX denotes a duplexer, the symbols BPFa, BPFb, and BPFc are band pass filters, the symbols AMPa and AMPb denote amplifying circuits, the symbols MIXa and MIXb denote mixers, the symbol OSC denotes an oscillator, and the symbol DIV denotes a frequency divider (a 25 synthesizer). MIXa modulates a signal frequency outputted from DIV by a modulation signal, BPFa allows only the signals of a transmitting-frequency band to pass through, and AMPa power-amplifies the signals to transmit from ANT via DPX. BPFb allows only the receiving-frequency-band signals of the signals outputted from DPX to pass through, and AMPb power-amplifies the passed signals. MIXb performs mixing of 30 frequency signals outputted from BPFc and received signals to output intermediate frequency signals IF.

[0055] As the duplexer DPX shown in Fig. 13, it is possible to use a dielectric duplexer having the structure shown in Figs. 10A to 10D. In addition, as the band pass filters BPFa, BPFb, and BPFc, it is possible to use the dielectric filter having the structure shown in Figs. 5A to 5D. In this way, an overall compact communication 35 apparatus is produced.

[0056] While the invention has been particularly shown and described with reference to preferred embodiments thereof, it will be understood by those skilled in the art that the forgoing and other changes in form and details may be made therein without departing from the spirit of the invention. 40 45 50

Claims

1. A dielectric filter comprising:

- an attenuation band in proximity to a pass band;
- a threshold-frequency position (B) of a deter-

mined maximum insertion loss being arranged close to a shoulder portion of a waveform exhibiting pass characteristics in which insertion losses increase in a region from the pass band to the attenuation band;

temperature characteristics of a dielectric material (1) being determined in such a manner that the shoulder portion moves toward the attenuation-band direction according to an increase and decrease in temperature.

2. The dielectric filter according to Claim 1, wherein the dielectric filter further comprises a plurality of dielectric resonators (12a-12d), at least one (12d) of the dielectric resonators being a trap resonator forming an attenuation pole in a region from the shoulder portion to the attenuation band, and temperature characteristics of the dielectric material (1) are determined in such a manner that resonant-frequency changes with respect to temperature changes in the trap resonator are smaller than those with respect to temperature changes in the other dielectric resonator.
3. The dielectric filter according to Claim 2, wherein the plurality of the dielectric resonators are integrally molded or integrally fired as a single dielectric block (1).
4. The dielectric filter according to Claim 1, wherein the dielectric filter is a band pass filter comprising a plurality of dielectric resonators (12a-12d) in which the pass band is used as the range of a resonant frequency.
5. The dielectric filter according to Claim 1, wherein the dielectric filter is a band block filter comprising a plurality of dielectric resonators in which the attenuation band is used as the range of a resonant frequency.
6. A dielectric duplexer comprising two dielectric filters in accordance with one of Claims 1, 2, 4, and 5, one of the two filters being a dielectric filter, in which the low-frequency band of the filter is an attenuation band and the high-frequency band thereof is a pass band, and the other filter being a dielectric filter, in which the low-frequency band of the filter is a pass band and the high-frequency band thereof is an attenuation band (1).
7. The dielectric duplexer according to Claim 6, wherein the two dielectric filters are integrally molded or integrally fired as a single dielectric block (1).
8. A communication apparatus comprising one of the dielectric filter (BPFa, BPFb, BPFc) in accordance

with one of Claims 1 to 5 and the dielectric duplexer (DPX) in accordance with one of Claims 6 and 7, which is disposed in a high-frequency circuit section.

5

10

15

20

25

30

35

40

45

50

55

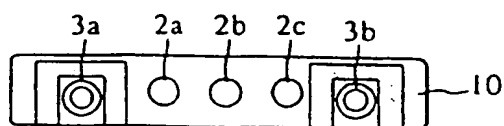


FIG. 1A

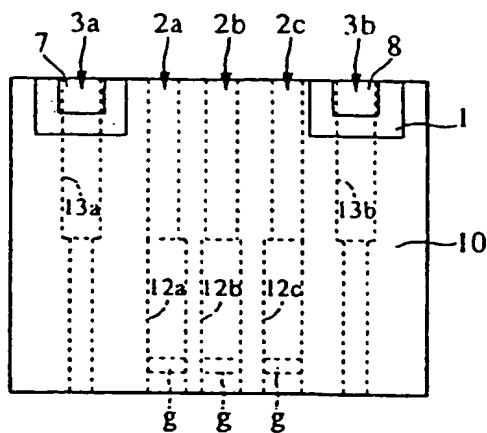


FIG. 1B

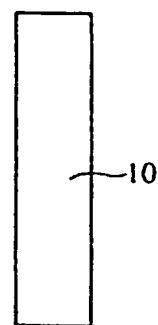


FIG. 1D

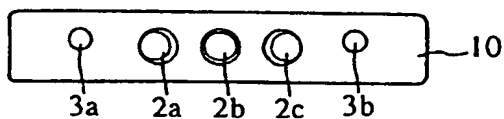


FIG. 1C

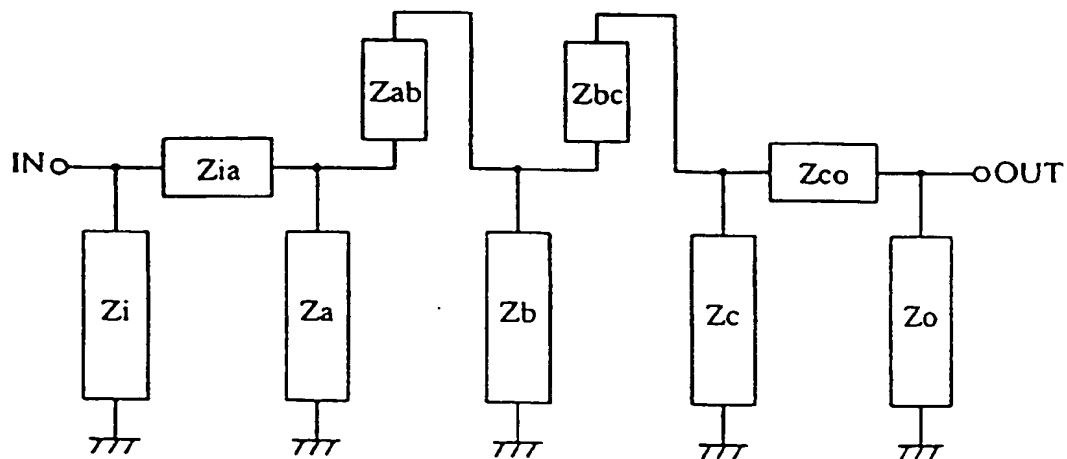


FIG. 2

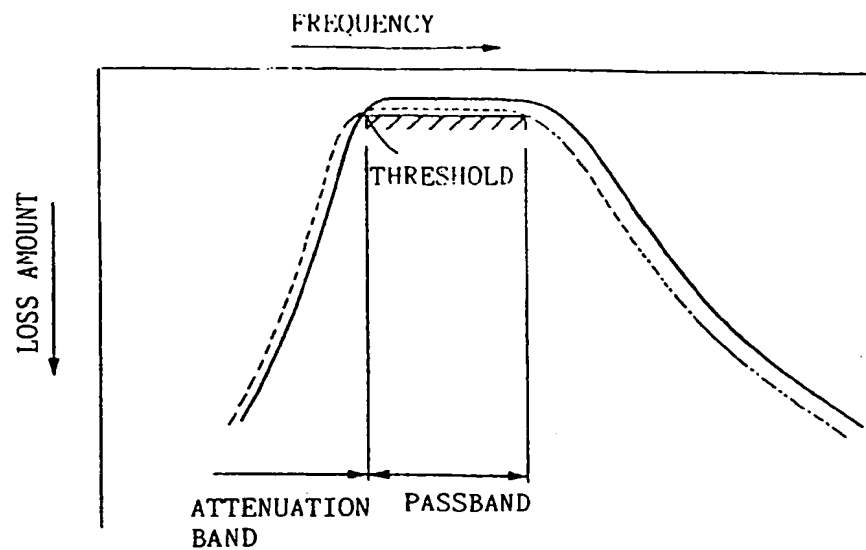


FIG. 3A

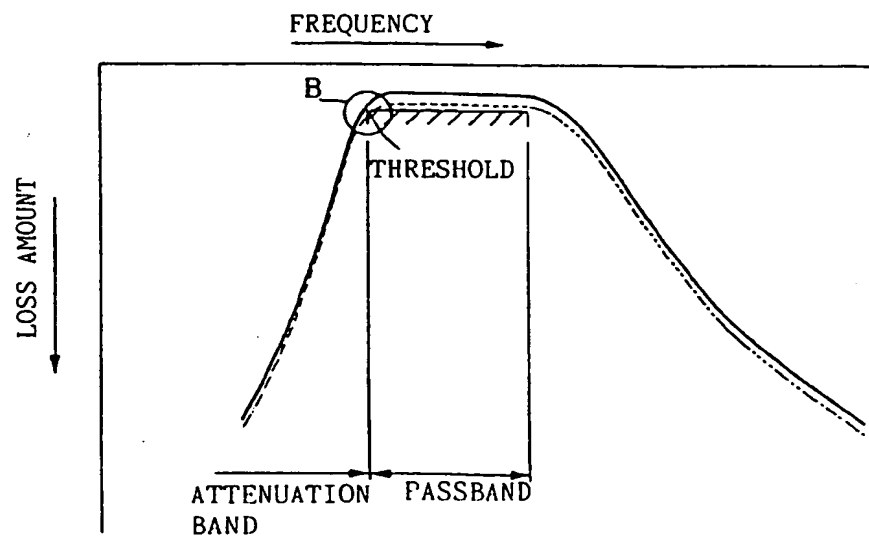


FIG. 3B

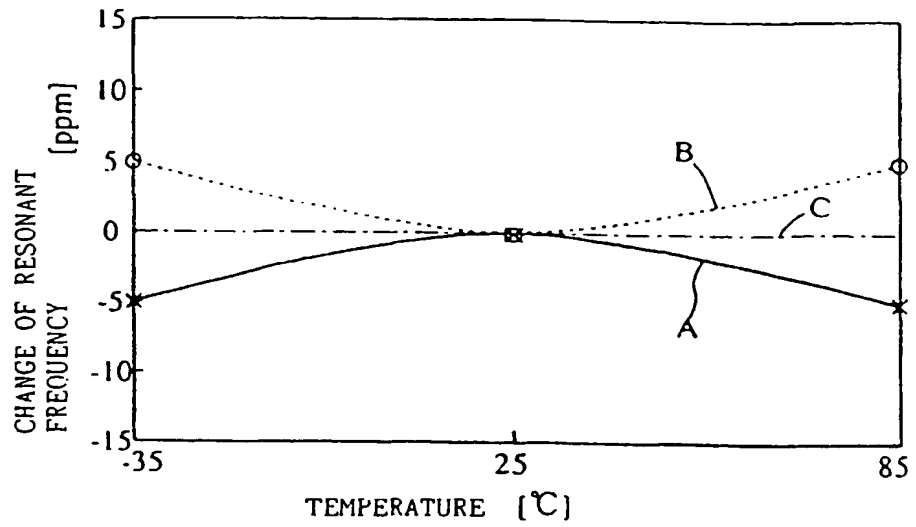


FIG. 4

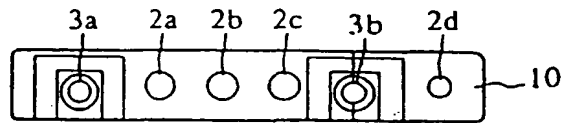


FIG. 5A

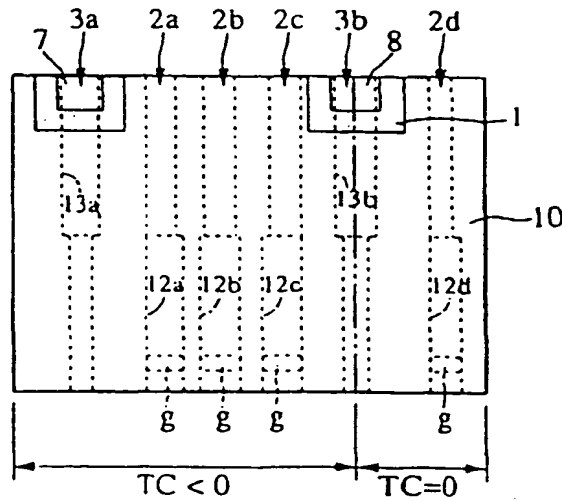


FIG. 5B

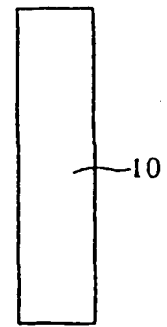


FIG. 5D

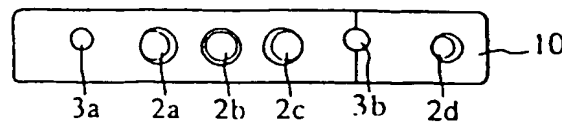


FIG. 5C

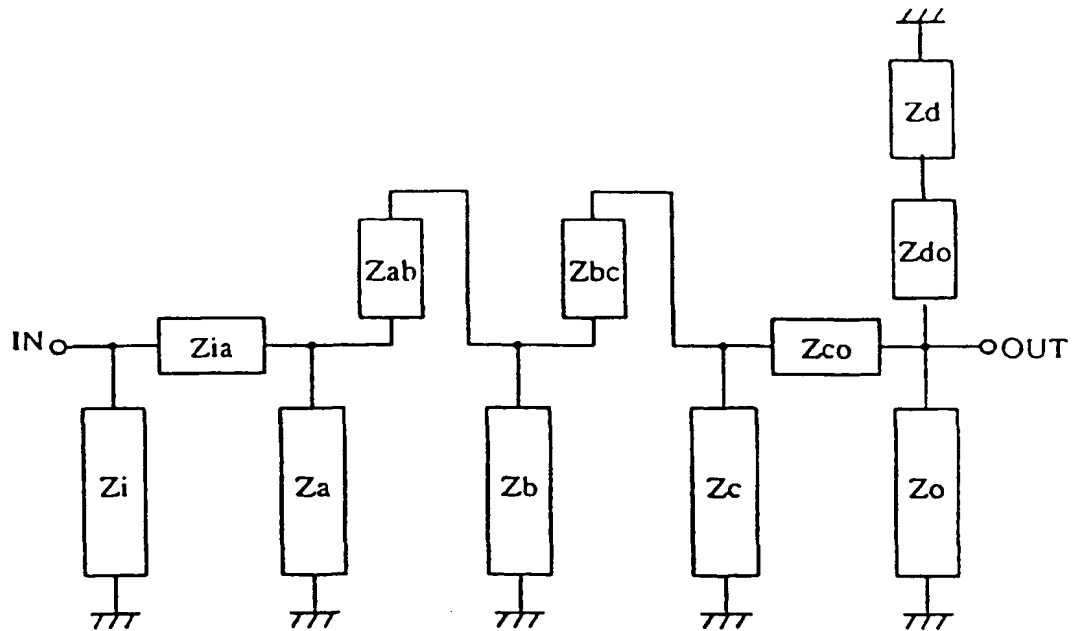


FIG. 6

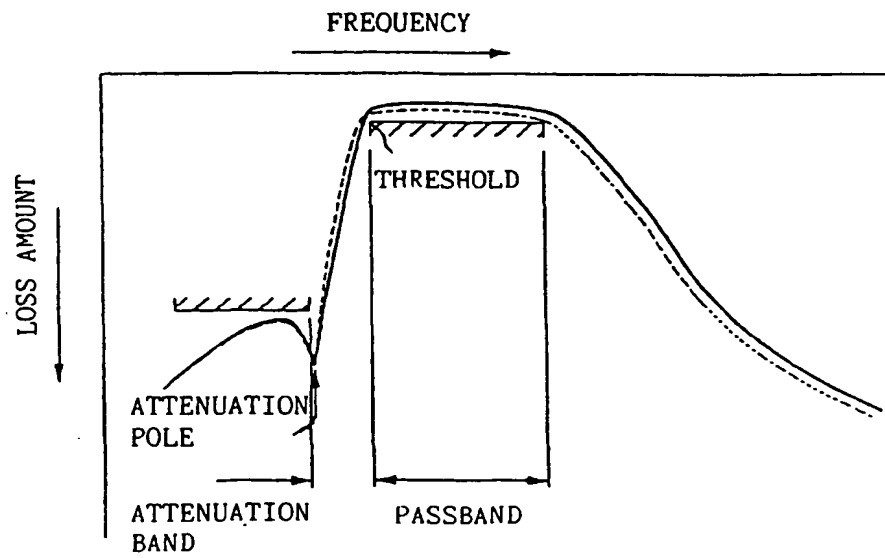


FIG. 7

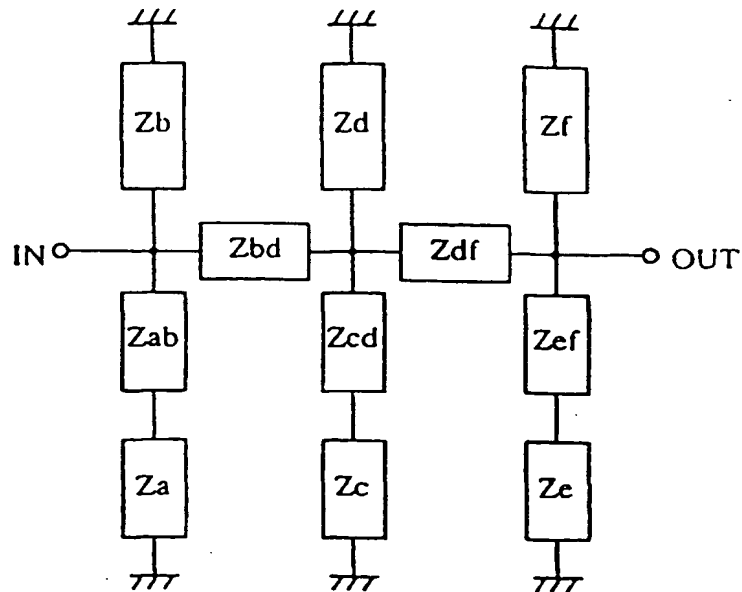


FIG. 8

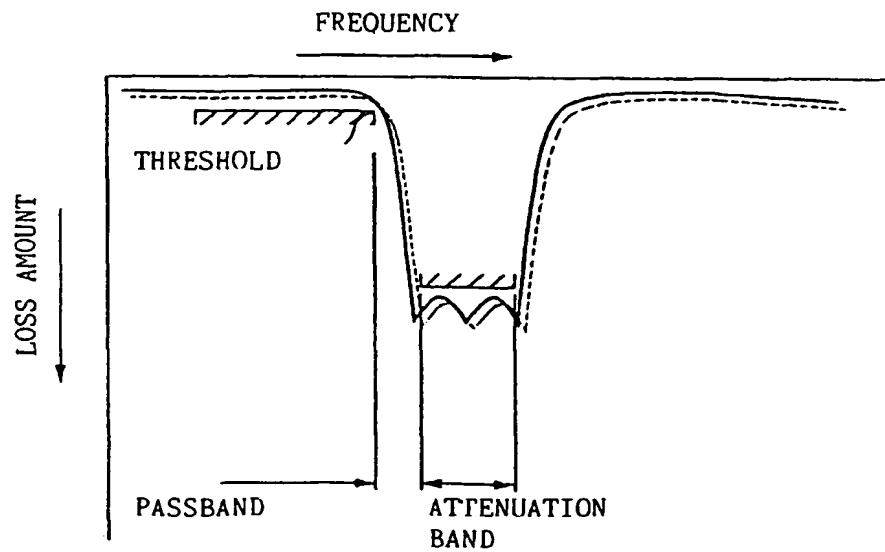


FIG. 9

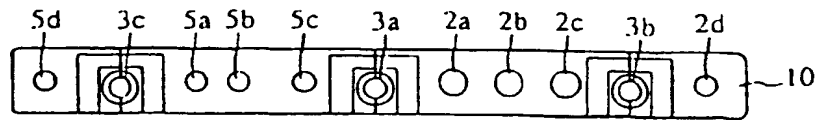


FIG. 10A

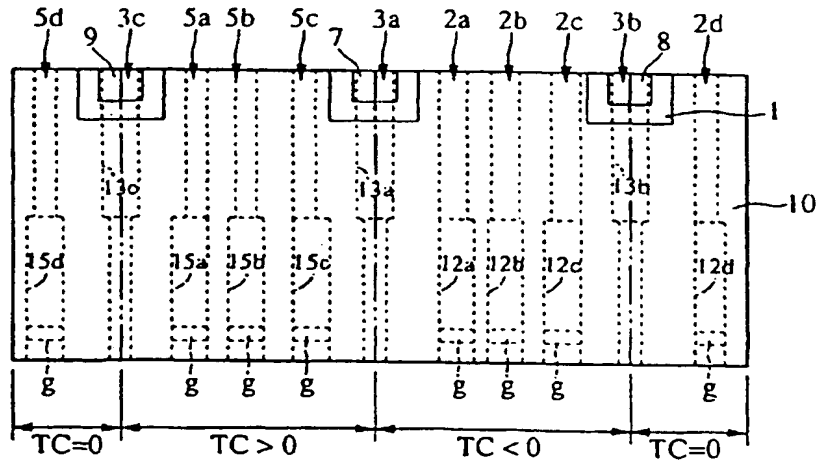


FIG. 10B

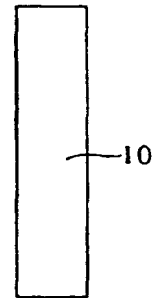


FIG. 10D

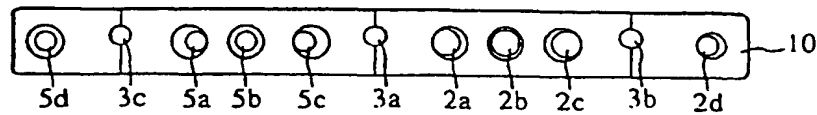


FIG. 10C

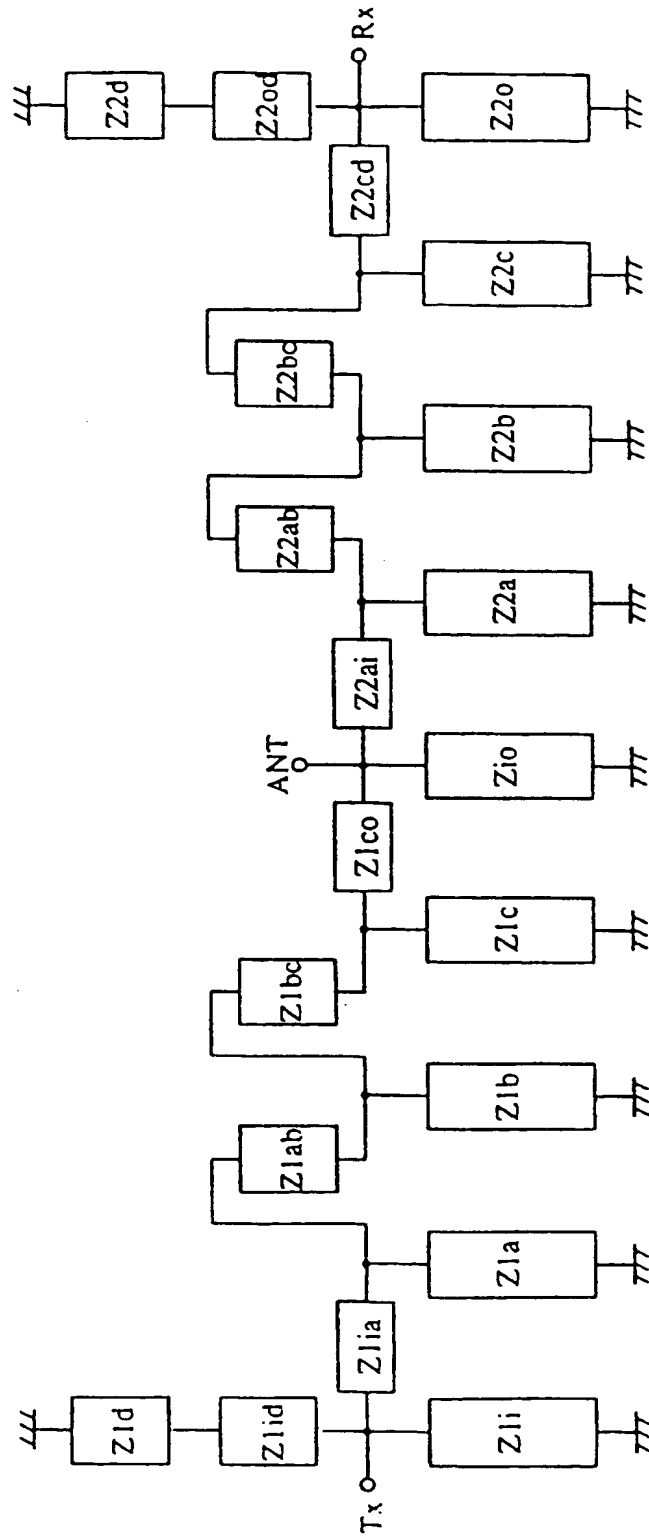


FIG. 11

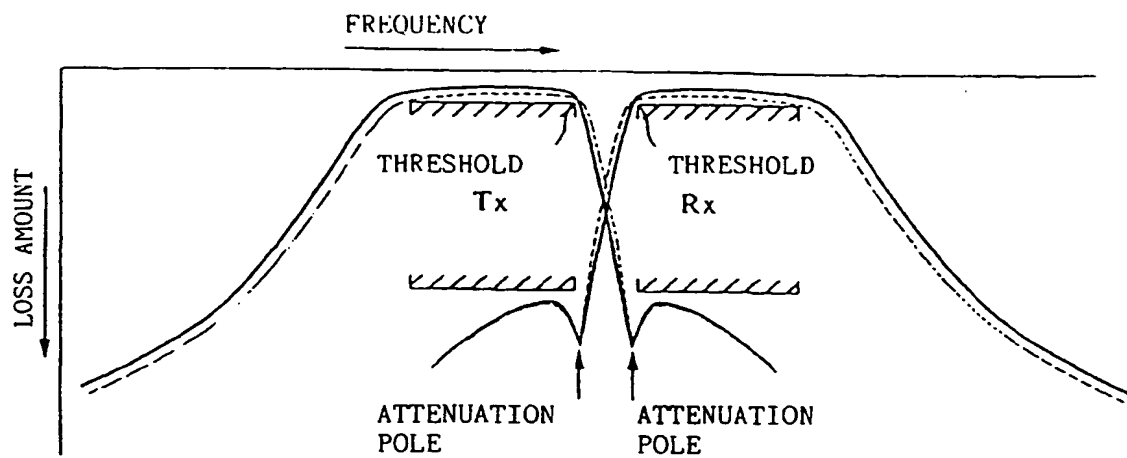


FIG. 12A

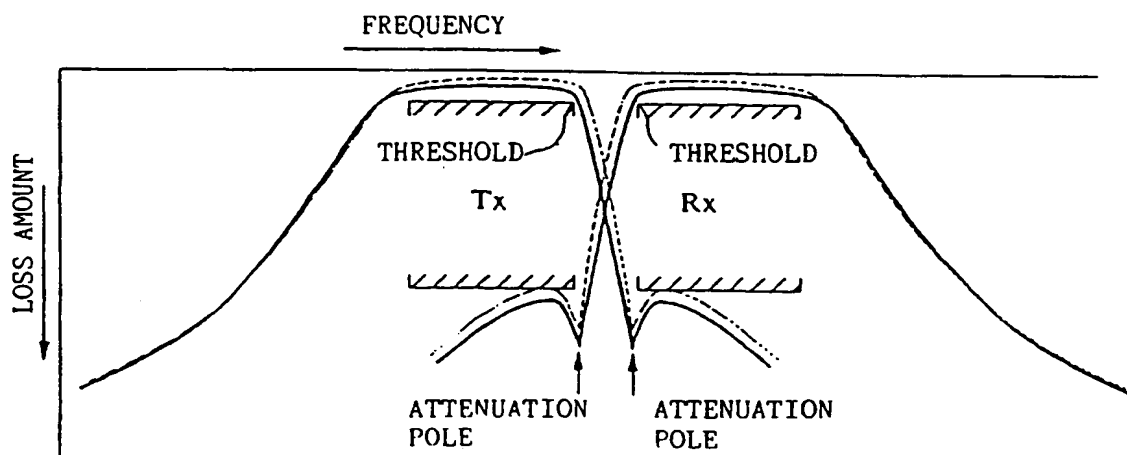


FIG. 12B

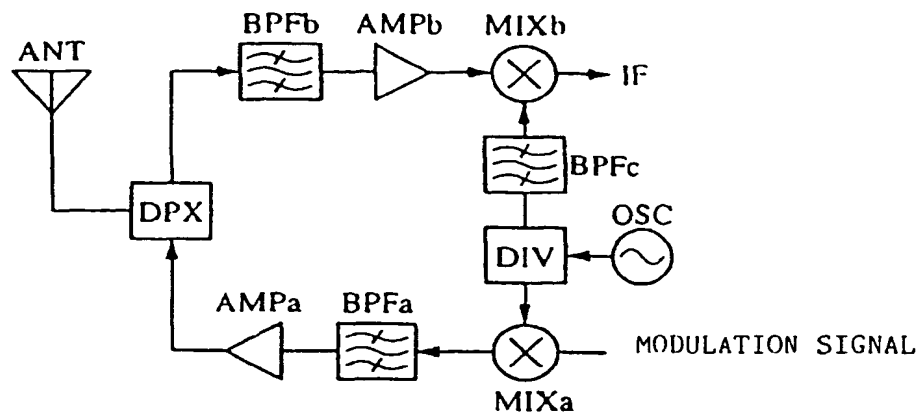


FIG. 13

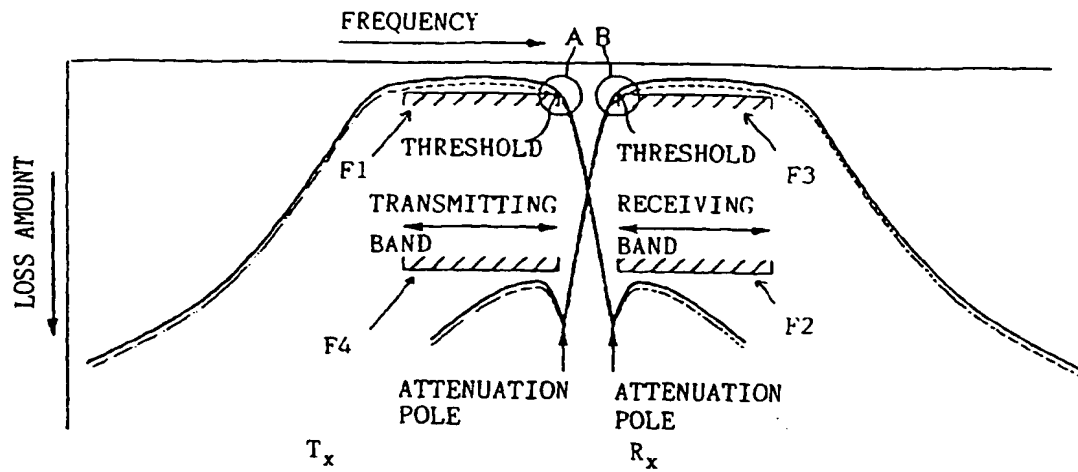


FIG. 14A

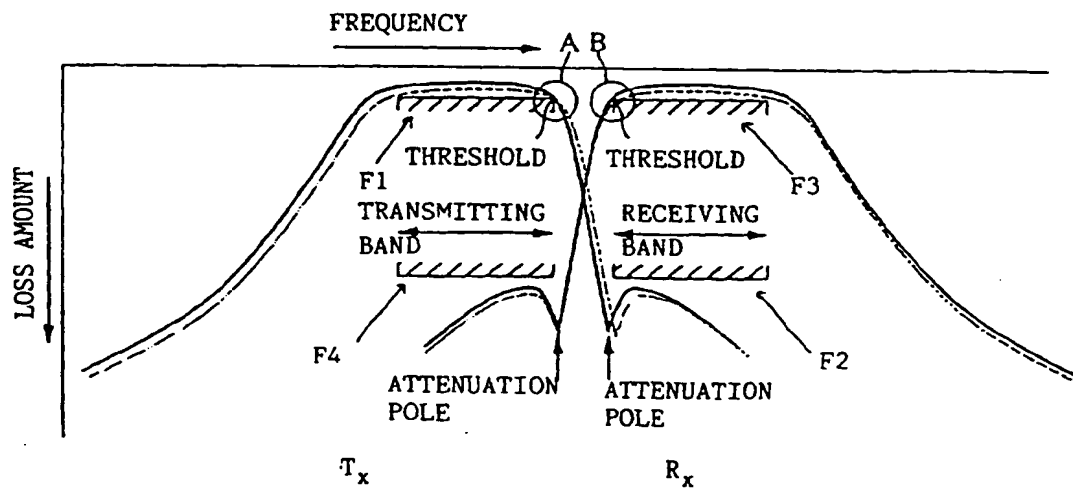


FIG. 14B



(19)

Europäisches Patentamt

European Patent Office

Office européen des brevets



(11)

EP 1 024 547 A3

(12)

EUROPEAN PATENT APPLICATION

(88) Date of publication A3:
27.03.2002 Bulletin 2002/13

(51) Int Cl.7: H01P 1/205, H01P 1/213

(43) Date of publication A2:
02.08.2000 Bulletin 2000/31

(21) Application number: 00100433.2

(22) Date of filing: 10.01.2000

(84) Designated Contracting States:
AT BE CH CY DE DK ES FI FR GB GR IE IT LI LU
MC NL PT SE
Designated Extension States:
AL LT LV MK RO SI

- Kato, Hideyuki, Murata Manufacturing Co., Ltd.
Nagaokakyo-shi, Kyoto-fu 617-8555 (JP)
- Hiroshima, Motoharu, Murata Manufact. Co., Ltd.
Nagaokakyo-shi, Kyoto-fu 617-8555 (JP)

(30) Priority: 28.01.1999 JP 1976799

(71) Applicant: Murata Manufacturing Co., Ltd.
Nagaokakyo-shi Kyoto-fu 617-8555 (JP)

(74) Representative: Schoppe, Fritz, Dipl.-Ing. et al
Schoppe, Zimmermann & Stöckeler,
Patentanwälte,
Postfach 71 08 67
81458 München (DE)

(72) Inventors:
• Tada, Hitoshi, Murata Manufacturing Co., Ltd.
Nagaokakyo-shi, Kyoto-fu 617-8555 (JP)

(54) Dielectric filter, dielectric duplexer, and communication apparatus

(57) There is disclosed a dielectric filter comprising: an attenuation band in proximity to a pass band; a threshold-frequency position (B) of a determined maximum insertion loss being arranged close to a shoulder portion of a waveform exhibiting pass characteristics in which insertion losses increase in a region from the pass band to the attenuation band; temperature characteris-

tics of a dielectric material being determined in such a manner that the shoulder portion moves toward the attenuation-band direction according to an increase and decrease in temperature. In the above dielectric filter, the deterioration of insertion-loss characteristics with respect to temperature changes is improved so that good characteristics are exhibited over a wide range of temperatures.

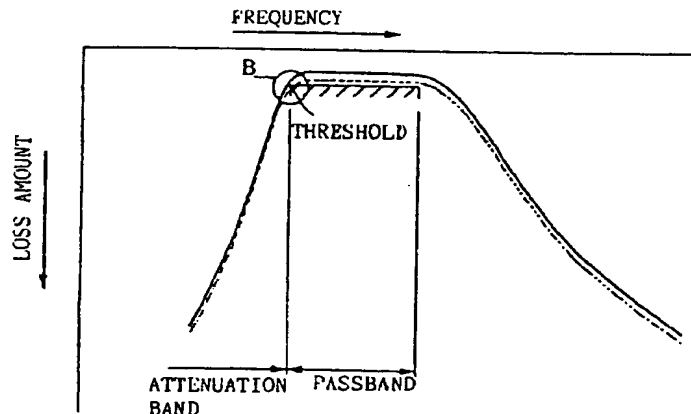


FIG. 3B

EP 1 024 547 A3



European Patent
Office

EUROPEAN SEARCH REPORT

Application Number
EP 00 10 0433

DOCUMENTS CONSIDERED TO BE RELEVANT			
Category	Citation of document with indication, where appropriate, of relevant passages	Relevant to claim	CLASSIFICATION OF THE APPLICATION (Int.Cl.7)
A	US 4 890 079 A (SASAKI KANEMI) 26 December 1989 (1989-12-26) * column 1, line 13-15; figures 1,14-19 *	1,4,6,8	H01P1/205 H01P1/213
A	PATENT ABSTRACTS OF JAPAN vol. 016, no. 349 (C-0967), 28 July 1992 (1992-07-28) & JP 04 104946 A (NGK INSULATORS LTD), 7 April 1992 (1992-04-07) * abstract *	1	
A	PATENT ABSTRACTS OF JAPAN vol. 1995, no. 02, 31 March 1995 (1995-03-31) -& JP 06 310903 A (TOKIN CORP), 4 November 1994 (1994-11-04) * abstract; figure 2 *	1	
A	PATENT ABSTRACTS OF JAPAN vol. 016, no. 048 (E-1163), 6 February 1992 (1992-02-06) & JP 03 250901 A (TAIYO YUDEN CO LTD), 8 November 1991 (1991-11-08) * abstract *	1	
			TECHNICAL FIELDS SEARCHED (Int.Cl.7)
			H01P
The present search report has been drawn up for all claims			
Place of search		Date of completion of the search	Examiner
THE HAGUE		4 February 2002	Den Otter, A
CATEGORY OF CITED DOCUMENTS			
X : particularly relevant if taken alone Y : particularly relevant if combined with another document of the same category A : technological background O : non-written disclosure P : intermediate document		T : theory or principle underlying the invention E : earlier patent document, but published on, or after the filing date D : document cited in the application L : document cited for other reasons & : member of the same patent family, corresponding document	

EPO FORM 1033 03 32 (P4400)

ANNEX TO THE EUROPEAN SEARCH REPORT ON EUROPEAN PATENT APPLICATION NO.

EP 00 10 0433

This annex lists the patent family members relating to the patent documents cited in the above-mentioned European search report.
The members are as contained in the European Patent Office EDP file on
The European Patent Office is in no way liable for these particulars which are merely given for the purpose of information.

04-02-2002

Patent document cited in search report		Publication date	Patent family member(s)	Publication date
US 4890079	A	26-12-1989	JP 1112801 A	01-05-1989
			JP 1706036 C	27-10-1992
			JP 3075081 B	29-11-1991
JP 04104946	A	07-04-1992	DE 69123015 D1	12-12-1996
			DE 69123015 T2	03-04-1997
			EP 0473347 A1	04-03-1992
			US 5185304 A	09-02-1993
JP 06310903	A	04-11-1994	NONE	
JP 03250901	A	08-11-1991	NONE	

EPO FORM P0453

For more details about this annex : see Official Journal of the European Patent Office, No. 12/82